



16592-2

IPW

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

GARY S. TOMPA, ET AL.

Application No.: 10/774,839

Filed: February 9, 2004

For: MICROELECTRONIC RADIATION
DETECTOR

Examiner: NYA

Group Art Unit: 2878

August 24, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56 and in accordance with the practice under 37 C.F.R. §§ 1.97 and 1.98, the Examiner's attention is directed to the documents listed on the enclosed PTO-1449. In accordance with the Official Gazette notice dated August 5, 2003, copies of cited U.S. Patents and U.S. published applications are not enclosed. Copies of the other cited references, however, are enclosed. It is respectfully requested that the PTO-1449 form be initialed and returned, indicating that the cited references have been considered.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first-class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on

August 24, 2004

Date of Deposit

Justin D. Petruzzelli (Reg. No. 52,118)

Name

Signature

August 24, 2004

Date of Signature

Applicants' undersigned attorney may be reached by telephone at (973) 597-2500.

All correspondence should continue to be directed to our address listed below.

Respectfully submitted,

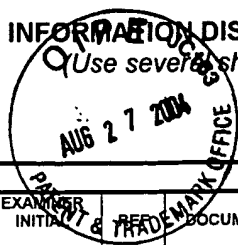


Justin D. Petruzzelli
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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	Docket Number (Optional) 16592-2	Application Number 10/774,839
	Applicant(s) Gary S. Tompa, et al.	
	Filing Date February 9, 2004	Group Art Unit 2878



U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
		2002/0174367	11/21/02	Kimmel et al.	713	201	

FOREIGN PATENT DOCUMENTS								
EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION	
							Yes	No
		EP 0 542 561 A1	05/19/93	Westrom, et al.	G01T1	00		
		JP 10132944	5/22/98	Jeon-Seo Park	G01T1	17		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
		Brent R. Blaes and Martin G. Buehler, "SEU/SRAM as a Process Monitor", IEEE Transactions on Semiconductor Manufacturing, Vol. 7, No. 3, August, 1994, Pages 319-324	

Examiner Signature	Date Considered
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	